

## **IN THE CLAIMS**

1-3. (Cancelled)

4. (Original) A method for correcting an inter-pin spotting amount error of a microarray produced by repeating an operation of simultaneously spotting a plurality of samples on a support by using a spotting device provided with a plurality of pins, the method comprising the steps of:

simultaneously spotting the same samples as controls on the support with all of the pins of the spotting device, where a plurality of samples are spotted on the support with the spotting device;

Measuring spotting amounts of the controls spotted with the respective pins of the spotting device to obtain correction parameters for inter-pin spotting amount errors; and

Correcting a measured value of each sample spot on the support by using the obtained correction parameters for the inter-pin spotting amount errors.

5. (Original) A method for correcting an inter-pin spotting amount error of a microarray according to claim 4, wherein information for identifying the pins used for immobilizing the samples to respective sample spot locations is obtained via positional information of wells on a well plate, which store the samples to be transferred to a microplate with the pins.

6-10. (Cancelled)